	Application No.	Applicant(s)	
Notice of Allowability	10/602,180	CAMPBELL, SCOT	T P.
	Examiner	Art Unit	
	William C. Choi	2873	
The MAILING DATE of this communication appears on the cover sheet with the correspondence address All claims being allowable, PROSECUTION ON THE MERITS IS (OR REMAINS) CLOSED in this application. If not included herewith (or previously mailed), a Notice of Allowance (PTOL-85) or other appropriate communication will be mailed in due course. THIS NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT RIGHTS. This application is subject to withdrawal from issue at the initiative of the Office or upon petition by the applicant. See 37 CFR 1.313 and MPEP 1308.			
1. A This communication is responsive to Amendment filed 9/10	<u>0/2004</u> .	•	
2. ☑ The allowed claim(s) is/are <u>1-13 and 15-25</u> .			
3. \boxtimes The drawings filed on <u>24 June 2003</u> are accepted by the E.	xaminer.		
4. ☐ Acknowledgment is made of a claim for foreign priority una) ☐ All b) ☐ Some* c) ☐ None of the: 1. ☐ Certified copies of the priority documents have 2. ☐ Certified copies of the priority documents have 3. ☐ Copies of the certified copies of the priority documents have International Bureau (PCT Rule 17.2(a)). * Certified copies not received: Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONM THIS THREE-MONTH PERIOD IS NOT EXTENDABLE. 5. ☐ A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give 6. ☐ CORRECTED DRAWINGS (as "replacement sheets") must	been received. been received in Application to file this communication to file the Application. itted. Note the attached EX are reason(s) why the oath oat the submitted.	on No ed in this national stage applica e a reply complying with the re AMINER'S AMENDMENT or Nor declaration is deficient.	quirements
(a) ☐ including changes required by the Notice of Draftspers	-	w (PTO-948) attached	
1) hereto or 2) to Paper No./Mail Date(b) including changes required by the attached Examiner's Paper No./Mail Date	s Amendment / Comment o		a haala) af
ldentifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in t	he header according to 37 C	FR 1.121(d).	B Dack) Of
7. DEPOSIT OF and/or INFORMATION about the depo attached Examiner's comment regarding REQUIREMENT			Note the
Attachment(s)			
1. Notice of References Cited (PTO-892)		nformal Patent Application (PT	O-152)
2. Notice of Draftperson's Patent Drawing Review (PTO-948)	Paper No	Summary (PTO-413), ./Mail Date	
 Information Disclosure Statements (PTO-1449 or PTO/SB/C Paper No./Mail Date	·	s Amendment/Comment s Statement of Reasons for All	OW/anco
of Biological Material	9. ☐ Other		o war los
Georgia Fops Supervisory Patent Examiner U.S. Patent and Trademark Office Technology Center 2800			

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Allowed Claims: 1-13 and 15-25.

REASONS FOR ALLOWANCE

The following is an examiner's statement of reasons for allowance: none of the prior art either alone or in combination disclose or teach of the claimed combination of limitations to warrant a rejection under 35 USC 102 or 103.

Specifically, with respect to independent claim 1, none of the prior art alone or in combination disclose or teach of a method for using a length dispersion of an etalon as claimed, specifically comprising selecting an etalon having a plurality of resonant frequencies which approximate target resonant frequencies based at least in part in consideration of a length dispersion of the etalon.

Specifically, with respect to independent claim 6, none of the prior art alone or in combination disclose or teach of a method for using a length dispersion of an etalon as claimed, specifically comprising selecting a length dispersion for the etalon suitable to cooperate with a material dispersion to produce a plurality of resonant frequencies which approximate target resonant frequencies.

Specifically, with respect to independent claim 15, none of the prior art alone or in combination disclose or teach of a method for using a length dispersion of an etalon as claimed, specifically comprising determining an impact of the length dispersion of the etalon on a plurality of resonant frequencies of the etalon and selecting the etalon for application in an optical system based at least in part on the length dispersion of the etalon.

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Specifically, with respect to independent claim 20, none of the prior art alone or in combination disclose or teach of a method for using a length dispersion of an etalon as claimed, specifically comprising determining an impact of a length dispersion of the etalon on a plurality of resonant frequencies of the etalon, comparing the plurality of resonant frequencies of the etalon with a plurality of target resonant frequencies and selecting the etalon for application in an optical system based at least in part on a result of the comparison.

CONCLUSION

Any inquiry concerning this communication or earlier communications from the examiner should be directed to William C. Choi whose telephone number is (571) 272-2324. The examiner can normally be reached on Monday-Friday from about 9:00 am to 6 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Georgia Y. Epps can be reached on (571) 272-2328. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should

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you have questions on access to the Private PAIR system, contact the Electronic

Business Center (EBC) at 866-217-9197 (toll-free).

W.C

William Choi Patent Examiner Art Unit 2873 October 3, 2004

Georgia Epps
Supervisory Patent Examiner
Technology Center 2800

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